

PATENT  
8026-1008

IN THE U.S. PATENT AND TRADEMARK OFFICE

Application of

Toshiya SHIMURA et al.

Conf. 7580

Application No. 09/973,762

Group 2643

Filed October 11, 2001

Examiner B. Taylor

METHOD OF MEASURING AND IMPROVING  
XDSL TRANSMISSION CHARACTERISTIC

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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

June 28, 2004

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.

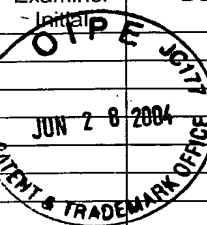
A concise explanation of the relevance of these items is that these references were cited by the Japanese Patent Office in an Official Action. A copy of the Japanese Official Action in which they were cited is attached hereto, with what is believed to be the pertinent portion enclosed in a wavy line. **An English translation of the enclosed portion is also attached hereto.**

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION		Attorney Docket No.: 8026-1008		Application No.: 09/973,762			
(Use several sheets if necessary)		Applicant: Toshiya SHIMURA et al.					
		Filing Date: October 11, 2001		Group Art Unit: 2643			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)	
							
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FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No	
	WO 99/53637	10/21/1999	INTERNATIONAL				
	JP 2000-13343	1/14/2000	JAPAN				
	JP 2002-511699	4/16/2002	JAPAN				
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							

\* Abstract provided for the Examiner's convenience